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cul	AA	2,810,324	10/1957	Marks						
an	AB	3,912,920	10/1975	Kubota						
an M M	AC	5,889,571	03/1999	Kim et al.						
all	AD	5,909,265	06/1999	Kim et al.						
all	AE	5,982,466	11/1999	Choi et al.						
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ou	AF	3-120503	05/1991	Japan						
one one one	AG	3-241311	10/1991	Japan						
cu	АН	5-19209	01/1993	Japan		:				
au	ΑI	7-318861	12/1995	Japan						
cue	AJ	10-90684	01/1998	Japan						
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que	AP	Hecht, "Optics," Addiso	n-Wesley Publish	ing co., 2 nd Edition, pp:298-99 .						
cu	AQ	Jenkins, Francis A., Han	vey E. White, Fun	damentals of Optics 3rd edition, pp: 492-3.						
euc	AR	M. Nam et al., "Wide-Vie	ewing-Angle TFT	-LCD with Photo-Aligned Four-Domain TN	Mode," SID 97	Digest, pp: 933-6.				
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ew	AA	5,657,105	08/1997	McCartney					
au	АВ	5,712,696	01/1998	Toko et al.					
cuc	AC	5,764,326	06/1998	Hasegawa et al.					
au	AĐ	5,767,994	06/1998	Kang et al.					
all	ΑE	5,784,139	07/1998	Chigrinov et al.					
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all	AF	4-7520	01/1992	Japan					
ou	AG	4-284421	10/1992	Japan					
ou	АН	4-350822	12/1992	Japan		_			
all	Al	5-34699	02/1993	Japan					
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an	АМ	0 525 473	02/1993	EPO					
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cu	AO	0 611 786	07/1996	EPO					
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cue	AP	D. Seo et al., "Invited A	ddress: Surface	Alignment of Liquid Crystals in LCDs," SID	93 Digest, pp:	954-6.			
cne	AQ	Y. limura, "Invited Addr	ess: Prospects o	of the Photo-Alignment Technique for LCD i	Fabrication," S	SID 97 Digest, pp: 3	11-4.		
cu	AR	R. Shashidhar et al., "A	Shashidhar et al., "A New Non-Rubbing Technique for Liquid-Crystal Alignment," SID 97 Digest, pp: 315-8.						
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au	AA	5,539,074	07/1996	Herr et al.			·	
M	АВ	5,576,862	11/1996	Sugiyama et al.				
w	AC	5,578,351	11/1996	Shashidhar et al.				
M	AD	5,602,661	02/1997	Schadt et al.				
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all	AF	0 708 354	04/1996	EPO				
W	AG	0 742 471	11/1996	EPO				
cul	АН	0 750 212	12/1996	EPO				
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all	AJ	64-60833	03/1989	Japan				
w	AK	1-251344	10/1989	Japan				
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au	АР	K. Lee et al., "Late-New Digest, pp: 638-41.	s Poster: Mecha	nism of UV Modification of LC Pretilt Angle	and Its Applic	cation to Two-Dom	ain TN-LCDs,"	SID 96
one	AQ	J. Kim et al., "Late News	J. Kim et al., "Late News Poster: Photo-Alignment of Liquid Crystals Using a New Photopolymer," SID 96 Digest, pp: 646-9.					
au	AR	Y. Saitoh et al., "Stabilit	Y. Saitoh et al., "Stability of UV-Type Two-Domain Wide-Viewing Angle TFT-LCD Panels," SID 96 Digest, pp: 662-5.					
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au	AA	5,447,662	09/1995	Herr et al.					
ou	АВ	5,453,862	09./1995	Toko et al.					
cu	AC	5,464,669	11/1995	Kang et al.					
Cuc	AD	5,479,282	12/1995	Toko et al.					
m	AE	5,538,823	07/19196	Park et al.					
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all	AQ	H. Soh et al., "The Reali	zation of Wide V	fiewing Angle TFT-LCDs Using Photo-Align	ment Method,	" Euro Display 96, p	p: 579-82.		
un	AR	J. Chen, "Mechanism of	J. Chen, "Mechanism of Liquid-Crystal Alignment by Polyimide Exposure to Linearly Polarized UV Light," SID 96 Digest, pp: 634-7.						
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all	AA	4,974,941	12/1990	Gibbons et al.				
w	AB	5,032,009	07/1991	Gibbons et al.				
cul	AC	5,073,294	12/1991	Shannon et al.				-
au	AD	5,296,321	03/1994	Kawanishi et al.				
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all	АР	J. West et al., "Polarized	l UV-Exposed Po	olyimide Films for Liquid-Crystal Alig	nment," SID 95 Dige	st, pp: 703-5.			
all	AQ	T. Hashimoto et al., "TN-877-80.	LCD with Quarte	ered Subpixels Using Polarized UV-L	ight-Irradiated Polyn	ner Orientation Film	ns," SID 95 Dig	gest, pp:	
M	AR	T. Saitoh et al., "A New I	Hybrid N-TB Mod	de LCD with Two Domain Pixels Fabr	icated Using a Photo	opolymer," Asia Dis	splay, pp: 589-9	92.	
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all	AP	A. Lien et al., "UV modif pp: 3108-11.	ication of surfac	ee pretilt of alignment layers of multidon	nain liquid crystal	<i>displays,"</i> Appl. P	hys. Lett. 62 (21), 11/20/95,		
all	AQ	M. Hasegawa, "Nematic and Technology, Vol. 8, I		Photo Alignment by Polyimide Exposur 241-8.	e to Linearly Pola	rized UV," Journal	of Photopolyme	r Science		
au	AR		M. Schadt, "Investigation of the Mechanism of the Surface-Induced Alignment of Liquid Crystals by Linearly Polymerized Photopolymers," SID 95 Digest, pp: 528-31.							
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al	AQ	Y. limura et al., "Invited Method," SID 94 Digest		o-Optic Characteristics of Amorphous and S	uper-Multido	main TN-LCDs Pre	pared by a Non-Rubbing			
all	AR		chadt et al., "Photo-Generation of Linearly Polymerized Liquid Crystal Aligning Layers Comprising Novel, Integrated Optically Patterned rders and Color Filters," Jpn. J. Appl. Phys. Vol. 34 (1995), pp: 3240-9, Part 1, No. 6A, June 1995.							
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